

### 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20131028000A Qualification of Carsem Suzhou (CSZ) as Additional Assembly and Test Site for Select Devices on QFN/SON package Change Notification / Sample Request

#### Dear Customer:

The purpose of this version A is to retract devices from this change notification. The retraction is for select devices that were inadvertently included and are not affected by this change. We apologize for any inconvenience this may have caused.

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN\_ww\_admin\_team@list.ti.com).

Sincerely,

PCN Team SC Business Services

### 20131028000A Attachment: 1

#### **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

BQ24072RGTR

Technical details of this Product Change follow on the next page(s).

PCN Numbe	r:	20	20131028000A PCN Date:					e:	04/11/2016	
Title: Qualification of Carsem Suzhou (CSZ) as Additional Assembly and Test Site for Select Devices on QFN/SON package										
<b>Customer Co</b>	ontact:	PC	N Ma	<u>nager</u>	De	pt:		Quality Services		
Change Type	e:						<u>.</u>			
Assemb				Assembly Process			Assembly	Mate	erials	
Design				Electrical Specification			Mechanical Specification			
	e		$\boxtimes$	Packing/Shipping/Labeling			Test Proce	ess		
Wafer E	Bump Site			Wafer Bump Material			Wafer Bur	np Pi	rocess	
Wafer F	ab Site			Wafer Fab Materials			Wafer Fab	Prod	cess	
				Part number change						
				PCN Details						
Description	of Change	<b>e</b> :								
Revision A is	to remove	sele		evices in the Product Affected ices were inadvertently added						
Qualification of Carsem Suzhou (CSZ) as Additional Assembly and Test Site for Select Devices on QFN/SON package.  Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.										
Reason for (	Change:									
Continuity of	supply.									
Anticipated	impact on	Fo	rm,	Fit, Function, Quality or Re	elial	ilic	ty (positiv	e/ı	negative):	
None										
Changes to	product id	lent	ifica	ation resulting from this Po	CN:					
Assembly S				<b>9</b>						
UTAC Thail				Assembly Site Origin (22)	)		ASO: N		ISF	
TI Malaysia				Assembly Site Origin (22)	_		ASO: MLA			
TI Clark - P				Assembly Site Origin (22)				0: Q		
Carsem Su:				Assembly Site Origin (22L)				0: C		
Sample prod  TEXAS INSTRUMI  MADE IN: 1  2DC:  MSL 2 /266  MSL 1 /238  OPT: ITEM:  LBL: 5/	S ENTS Malaysia 20: DC/1 YEAR 5C/UNLIM	SEA 03/	G L DT 29/0	(not actual product label) (1P (Q) (31) (4W (P) (2P)	) \$  ) 2  T)L ) TI	00 .01 KY /:	(1T) 752 (SHE (21L)	03: 17ML 348	-A 3SI2 3317 :USA	

ASSEMBLY SITE CODES: NSE = J, TI-Malaysia = K, TI-Clark = I, Carsem Suzhou = F

Product Affected:			
BQ24072RGTR	BQ24314ADSGT	SN1004052RTER	TPS51461RGET
BQ24072RGTRG4	BQ24314ADSGTG4	TLV62065DSGR	TPS51462RGER
<del>BQ24072RGTT</del>	BQ24314DSGR	TLV62065DSGT	TPS51462RGET
<del>BQ24072RGTTG4</del>	BQ24314DSGRG4	TPS2540ARTER	TPS53311RGTR
BQ24075RGTR	BQ24314DSGT	TPS2540ARTET	TPS53311RGTT
BQ24075RGTRG4	BQ24314DSGTG4	TPS2541ARTER	TPS53312RGTR
BQ24075RGTT	BQ24315DSGR	TPS2541ARTET	TPS53312RGTT
BQ24075RGTTG4	BQ24315DSGRG4	TPS2541RTER	TPS54319RTER
BQ24210DQCR	BQ24315DSGT	TPS2541RTET	TPS54319RTET
BQ24210DQCT	BQ24315DSGTG4	TPS2546RTER	TPS62065DSGR
BQ24300DSGR	BQ24316DSGR	TPS2546RTET	TPS62065DSGT
BQ24300DSGRG4	BQ24316DSGRG4	TPS2554DRCR	TPS62090RGTR
BQ24300DSGT	BQ24316DSGT	TPS2554DRCT	TPS62090RGTT
BQ24300DSGTG4	BQ24316DSGTG4	TPS2560DRCR	TPS62091RGTR
BQ24304DSGR	FX006	TPS2560DRCT	TPS62091RGTT
BQ24304DSGRG4	FX016	TPS51200DRC/2801	TPS62092RGTR
BQ24304DSGT	HPA00512DRCR	TPS51200DRCR	TPS62092RGTT
BQ24304DSGTG4	HPA00810RGTR-1/2	TPS51200DRCR/2801	TPS62093RGTR
BQ24313DSGR	HPA00935RGTR	TPS51200DRCRG4	TPS62093RGTT
BQ24313DSGT	HPA01187DSGR	TPS51200DRCT	
BQ24314ADSGR	SN0803054DRCR	TPS51200DRCTG4	
BQ24314ADSGRG4	SN0803054DRCRG4	TPS51461RGER	

## **Qualification Data**

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.							
Qual	Veh	nicle # 1: TPA311	17D2RHBR (MSL2-26	OC)			
Package Construction Details							
Assembly Site:	CAF	RSEM SUZHOU	Mold Compound:	SID#4	41086		
# Pins-Designator, Family:	32-	RHB, VQFN	Mount Compound:	SID#43	35143		
Lead frame (Finish, Base): NiPdAu, Cu Bond Wire:				1.3 Mil Dia., Cu			
Qualification:  Plan  Test Results							
Reliability Test		Conditions		Sample Size/Fail			
				Lot#1	Lot#2	Lot#3	
**High Temp. Storage Bake		170C (420hrs)		77/0	77/0	77/0	
**Biased HAST		130C/85%RH (96	0C/85%RH (96hrs)		77/0	77/0	
**Autoclave 121C		121C, 2 atm (96	C, 2 atm (96 Hrs)		77/0	77/0	
**T/C -65C/150C		-65C/+150C (500 Cyc)		77/0	77/0	77/0	
Manufacturability		(per mfg. Site specification)		Pass	Pass	Pass	
Moisture Sensitivity		(level 2 @ 260C p	oeak +5/-0C)	12/0	12/0	12/0	
Notes **- Preconditioning sequence: Level 3-260C.							

Qual Vehicle #2: TPA6132A2RTER (MSL2-260C)							
Package Construction Details							
Assembly Site: CARSEM SUZH		Mold Compound:	SID#441086				
# Pins-Designator, Family:	16-RTE, WQFN	Mount Compound:	SID#43	5933			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.96 Mil Dia., Cu				
Qualification:  Plan							
Dolinkility Toot	Conditions		Sample Size/Fail				
Reliability Test	Conditions	Conditions		1	_ot#2		
**Autoclave 121C	121C, 2 atm (96	Hrs)	77/0		77/0		
**T/C -65C/150C	-65C/+150C (500	) Cyc)	77/0		77/0		
Manufacturability	(per mfg. Site spe	ecification)	Pass		-		
Notes **- Preconditioning	sequence: Level 2-26	OC.					
Qual Vehicle # 3: TPS2540RTER (MSL2-260C)							
Package Construction Details							
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#441086				
# Pins-Designator, Family:	16-RTE, WQFN	Mount Compound:	SID#435143				
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	: 1.98 Mil Dia., Cu				
Qualification:  Plan							
D. P. J. W. T. J.				Sample Size/Fail			
Reliability Test	Conditions		Lot#1	Lot#2	Lot#3		
High Temp Life Test	125C (168 Hrs)	125C (168 Hrs)		80/0	80/0		
**T/C -65C/150C	-65C/+150C (500	-65C/+150C (500 Cyc)		77/0	-		
Notes **- Preconditioning sequence: Level 2-260C.							
Reference Qualification Data							

Reference Edanneation Data								
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.								
Qual Vehicle # 1: 2ELVC412CDRTJR (MSL2-260C)								
Package Construction Details								
Assembly Site:	CA	RSEM SUZHOU	Mold Compour	nd:	SID#	441086		
# Pins-Designator, Family:	20-	RTJ, WQFN	Mount Compour	nd:	SID#	D#435143		
Lead frame (Finish, Base):	NiP	dAu, Cu	Bond Wire: 1.0			0 Mil Dia., Cu		
Qualification:  Plan  Test Results								
Reliability Test		Conditions		Sample Size/Fail		Fail		
Reliability Test				Lot#1		Lot#2	Lot#3	
**High Temp. Storage Bake		170C (420hrs)			7/0	77/0	77/0	
**Autoclave 121C		121C, 2 atm (96 Hrs)		77/0		77/0	77/0	
**T/C -65C/150C		-65C/+150C (500 Cyc)		77/0		77/0	77/0	
Manufacturability		(per mfg. Site specification)		Pass		Pass	Pass	
Moisture Sensitivity		(level 2 @ 260C p	peak +5/-0C) 12/0 -		-			
Notes **- Preconditioning sequence: Level 2-260C.								

Qual Vehicle # 2: ONET8501PBRGTR (MSL2-260C)							
Package Construction Details							
Assembly Site:	CARSEM SUZHOU	Mold Compoun	d: SID#	#441086			
# Pins-Designator, Family:	·			nd: SID#435143			
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wir	e: 1.0 l	Mil Dia., C	u		
Qualification:  Plan	☐ Test Results			<u> </u>			
B !! ! !!!! . T . !	0 1111		San	nple Size/	'Fail		
Reliability Test	Conditions	Conditions		Lot#2	Lot#3		
**High Temp. Storage Bake	170C (420hrs)	77/0 77/0		77/0			
**Autoclave 121C	121C, 2 atm (96	Hrs)	77/0	77/0	77/0		
**T/C -65C/150C	-65C/+150C (50C		77/0	77/0	77/0		
Manufacturability (Assembly	) (per mfg. Site spe	ecification)	Pass	Pass	Pass		
Moisture Sensitivity	(level 2 @ 260C p		12/0	-	-		
	sequence: Level 2-260						
Qual	Vehicle # 3: TPS51	728RHAR (MSL3-260	C)				
	Package Constr	uction Details					
Assembly Site	e: CARSEM SUZHOU	Mold Compound:	SID#44	41086			
# Pins-Designator, Famil	y: 20-RTJ, VQFN	Mount Compound:	SID#43	35143			
Lead frame (Finish, Base		Bond Wire:					
Qualification: Plan Strest Results							
B. P. L. W. T. J.	0 1111	Conditions		Sample Size/Fail			
Reliability Test	Conditions			Lot#2	Lot#3		
**High Temp. Storage Bake	170C (420 Hrs)		77/0	77/0	77/0		
**Autoclave 121C	121C, 2 atm (96 H	lrs)	76/0	75/0	77/0		
**T/C -65C/150C	-65C/+150C (500		77/0	77/0	77/0		
Manufacturability	(per mfg. Site spec	cification)	Pass	Pass	Pass		
Moisture Sensitivity	(level 3 @ 260C pe	eak +5/-0C)	12/0	-	-		
Notes **- Preconditioning	sequence: Level 3-260	60C.					
Qual	Vehicle # 4: TPS53	211RGTR (MSL2-260	C)				
	Package Constr	uction Details					
Assembly Site:	CARSEM SUZHOU	Mold Compound:	SID#44	41086			
# Pins-Designator, Family:		Mount Compound:					
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:		Dia., Cu			
Qualification: Plan	☐ Test Results			2.4., 04.			
			San	nple Size/	'Fail		
Reliability Test	Conditions		Lot#1	Lot#2	Lot#3		
**Biased HAST	130C/85%RH (96	hrs)	77/0	76/0	77/0		
**High Temp. Storage Bake	170C (420hrs)	-,	77/0	77/0	77/0		
**Autoclave 121C	121C, 2 atm (96	Hrs)	77/0	77/0	77/0		
**T/C -65C/150C	-65C/+150C (50C		77/0	77/0	77/0		
Manufacturability (Assembly			Pass	Pass	Pass		
Moisture Sensitivity	(level 2 @ 260C p		12/0	-	-		
	sequence: Level 2-260		, 0	1	1		
1. Coordinated ming Soquerios. Lovel 2. 2000.							

Qual Vehicle # 5: UCD9211RHAR (MSL3-260C)							
Package Construction Details							
Assembly Site: 0	CARSEM SUZHOU	Mold Compound:	SID#441086				
# Pins-Designator, Family: 4	O-RHA, VQFN	Mount Compound:	SID#43	5143			
Lead frame (Finish, Base):	liPdAu, Cu	Bond Wire:	0.8 Mil	Dia., Cu			
Qualification:  Plan	☐ Test Results						
Reliability Test	Conditions		Sam	Fail			
Reliability Test			Lot#1	Lot#2	Lot#3		
**High Temp. Storage Bake	170C (420hrs)	170C (420hrs)		77/0	77/0		
**Autoclave 121C	121C, 2 atm (96	atm (96 Hrs)		77/0	77/0		
**T/C -65C/150C	-65C/+150C (500	-65C/+150C (500 Cyc)		77/0	77/0		
Salt Atmosphere	24 hrs	24 hrs		22/0	22/0		
Manufacturability (Assembly)	(per mfg. Site spe	(per mfg. Site specification)		Pass	Pass		
Moisture Sensitivity	(level 3 @ 260C p	(level 3 @ 260C peak +5/-0C)		-	-		
Notes **- Preconditioning sequence: Level 3-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com